

# MOSFET - Power, Single N-Channel

## 100 V, 65 mΩ, 13 A

# **NVTFS070N10MCL**

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFWS070N10MCL Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	100	V
Gate-to-Source Voltage	Э		V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	13	Α
Current R <sub>0JC</sub> (Notes 1, 2, 3)	Steady	T <sub>C</sub> = 100°C		9.0	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	25	W
R <sub>θJC</sub> (Notes 1, 2)		T <sub>C</sub> = 100°C		12	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	4.5	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C	1	3.2	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	2.9	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C	1	1.5	
Pulsed Drain Current	T <sub>C</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	47	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 0.5 A)			E <sub>AS</sub>	423	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C
Source Current (Body D	iode)		IS	19	Α

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

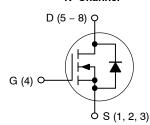
#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 2)	$R_{\theta JC}$	6.0	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	51	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
100 V	65 mΩ @ 10 V	13 A	
	90 mΩ @ 4.5 V	157	

#### N-Channel





#### WDFN8 (μ8FL) CASE 511AB



**MARKING** 

**DIAGRAM** 



WDFNW8 (u8FL WF) CASE 515AN



XXXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week

■ = Vork vveek = Pb–Free Package

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					1	1	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> =	250 μΑ	100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				67		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$				1.0	
		V <sub>DS</sub> = 100 V	T <sub>J</sub> = 125°C			100	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	s = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 15 μΑ	1.0		3.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 3 A		54	65	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 2 A		72	90	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 10 V, I <sub>E</sub>	<sub>O</sub> = 3 A		11		S
CHARGES, CAPACITANCES & GATE RES	SISTANCE				•	•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 50 V			305		
Output Capacitance	C <sub>OSS</sub>				135		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				1.9		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 50 \text{ V}; I_D = 2 \text{ A}$ $V_{GS} = 10 \text{ V}, V_{DS} = 50 \text{ V}; I_D = 3 \text{ A}$			2.7		
					5.5		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.6		
Gate-to-Source Charge	Q <sub>GS</sub>				1.0		nC
Gate-to-Drain Charge	Q <sub>GD</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 50 \text{ V}; I_D = 3 \text{ A}$			0.6		1 '
Plateau Voltage	V <sub>GP</sub>				2.6		V
SWITCHING CHARACTERISTICS (Note 5)					•	•	•
Turn-On Delay Time	t <sub>d(ON)</sub>				5.1		
Rise Time	t <sub>r</sub>	VGS = 10 V. VDS	s = 50 V.		1.3		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 10 \text{ V}, V_{DS}$ $I_D = 3 \text{ A}, R_G$	= 6 Ω		12.1		ns
Fall Time	t <sub>f</sub>				2.8		1
DRAIN-SOURCE DIODE CHARACTERIST	rics				•	•	•
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3 A	, T <sub>J</sub> = 25°C		0.84	1.3	V
		$V_{GS} = 0 \text{ V}, I_S = 3 \text{ A},$	T <sub>J</sub> = 125°C		0.72		
Reverse Recovery Time	t <sub>RR</sub>				19		ns
Reverse Recovery Charge	Q <sub>RR</sub>	VGS = 0 V, di/dt =	100 A/us.		8		nC
Charge Time	t <sub>S</sub>	I <sub>S</sub> = 1 A			9		
Discharge Time	t <sub>D</sub>				10		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

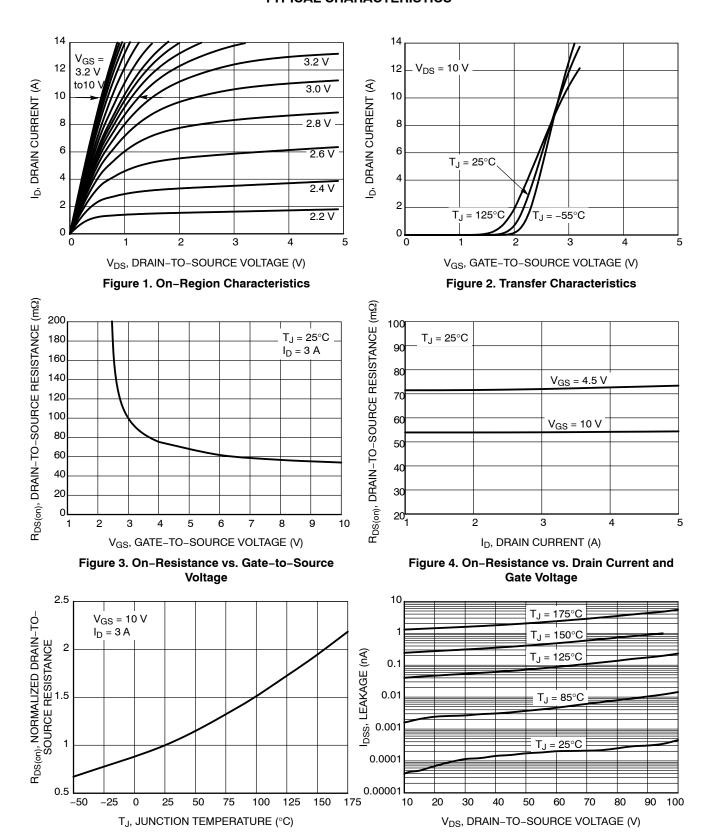


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

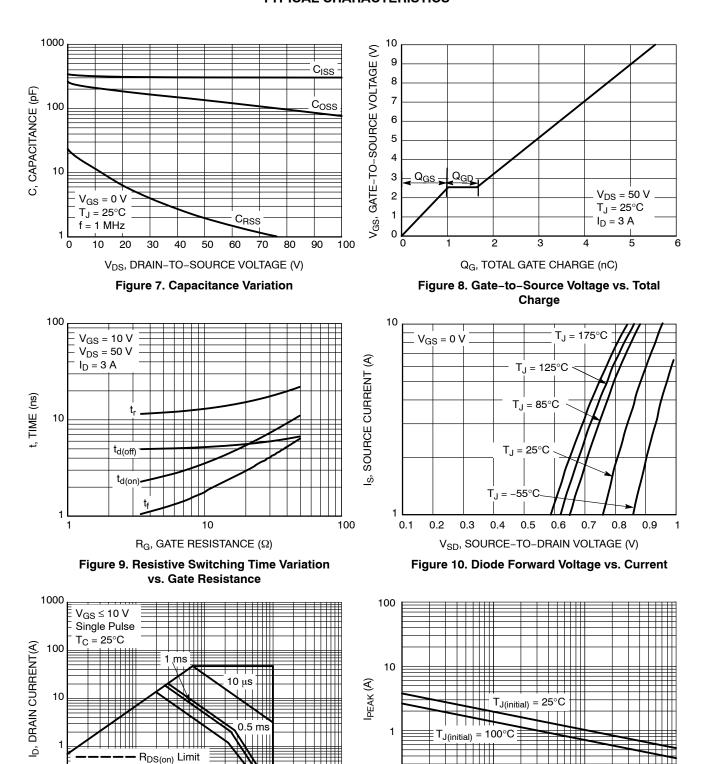


Figure 11. Maximum Rated Forward Biased Safe Operating Area

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

10

10 ms

100

Thermal Limit

Package Limit

0.1

0.1

TIME IN AVALANCHE (s) Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

0.001

0.0

0.0001

1000

0.1

0.00001

#### **TYPICAL CHARACTERISTICS**

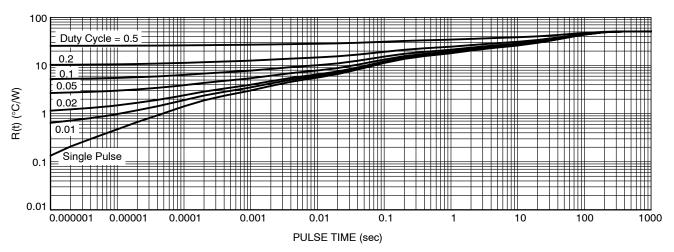


Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

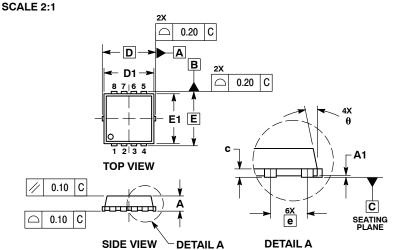
Device	Marking	Package	Shipping <sup>†</sup>
NVTFS070N10MCLTAG	70L1	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFWS070N10MCLTAG	70W1	WDFN8 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

**DATE 23 APR 2012** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
  PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		0	.130 BSC	;
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0	.130 BSC	;
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е	0.65 BSC			(	0.026 BS	0
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °



#### **GENERIC MARKING DIAGRAM\***

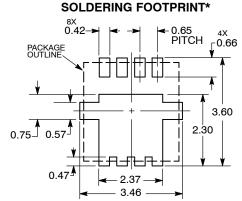


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

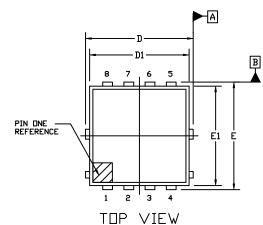
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

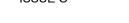
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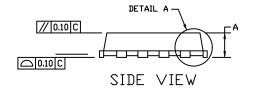


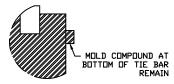
#### NDTES:

- 1. DIMENSIONING AND TOLERANCING PER.ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

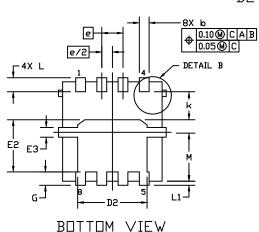
	PLATED AREA
DETAIL	C C SEATING PLANE

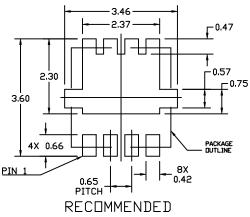
	MILLIMETERS				
DIM	MIN.	NDM.	MAX.		
A	0.70	0.75	0.80		
A1	0.00		0.05		
ø	0.23	0.30	0.40		
n	0.15	0.20	0.25		
D	3.05	3.30	3.55		
D1	2.95	3.05	3.15		
D2	1.98	2.11	2.24		
Ε	3.05	3.30	3.55		
E1	2.95	3.05	3.15		
E2	1.47	1.60	1.73		
E3	0.23	0.30	0.40		
a		0.65 BSC			
G	0.30	0.41	0.51		
K	0.65	0.80	0.95		
٦	0.30	0.43	0.59		
L1	0.06	0.13	0.20		
М	1.40	1.50	1.60		





DETAIL B





MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)		

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